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SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 196880US2 SRD		SERIAL NO. 09/652,010	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Katsuyuki NAITO et al.					
JUN 2 1 2002		<i>\$1</i>		FILING DATE 08/31/00		GROUP 8664 2653	
EXAMINER	- ANCI	(d)		U.S. PATENT DOCUMENTS			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
8√	AA	6,197,399	03/06/01	NAITO et al.	_		
₽√	AB	6,125,095	09/26/00	GEMMA et al.			
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		OTHER RE	FERENCES (Including Author, Title, Date, Pertine	nt Pages, e	tc.)	
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Form PTO 1449	U.S. DEPARTMENT OF COMMERCE			ATTY DOCKET NO. 196880US2SRD SERIAL NO. 09/652,010					
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LIST OF	REFE	RENCES CITED BY AF	PLICANT	Katsuyuki NAITO, et al.					
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				August 31, 2000		265 3			
7				U.S. PATENT DOCUMENTS					
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE		
BV	AA	5.027,216	06/25/91	I. TAKANASHI, et al.		-			
RV	AB	3,801,966	04/02/74	M. TERAO	1				
RV	AC	4,956,714	09/11/90	I. TAKANASHI, et al.		1	ECEIVED		
ŽV	AD	5,162,819	11/10/92	K. SAKAI, et al.		{			
R1/	ΑE	5,479,384	12/26/95	P. TOTH, et al.		A	PR 1 1 2003		
BV	AF	5,270,995	12/14/93	K. WADA, et al.		- .			
RV	AG	4,701,880	10/20/87	K. ICHIHARA		lechi	nology Center 20ਹ0		
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RV	AO	57-123541	08/02/82	JAPAN (with English Abstract)		YES	X NO		
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RV BV	AP AQ AR		+	<u> </u>		YES	X		
RV BV	AP AQ AR AS		+	<u> </u>		YES	X		
RV BV	AP AQ AR AS AT		+	<u> </u>		YES	X		
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BV	AP AQ AR AS AT AU AV	OTHER R Patent Abstracts of Ja	06/26/98 EFERENCES (Ipan, JP 60-212 Ipan, JP 57-138	JAPAN (with English Abstract) Including Author, Title, Date, Pertinen 2843, October 25, 1985	t Pages, e		X		
BV	AP AQ AR AS AT AU AV AW	OTHER R Patent Abstracts of Ja	06/26/98 EFERENCES (Ipan, JP 60-212 Ipan, JP 57-138	JAPAN (with English Abstract) Including Author, Title, Date, Pertinen 2843, October 25, 1985 5445, August 21, 1982		tc.)	X		
BV	AP AQ AR AS AT AU AV AW AX	OTHER R Patent Abstracts of Ja	D6/26/98 EFERENCES (Epan, JP 60-212 Epan, JP 57-138 Epan, JP 10-288	JAPAN (with English Abstract) Including Author, Title, Date, Pertinen 2843, October 25, 1985 5445, August 21, 1982		tc.)	X X		

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ATTY DOCKET NO. SERIAL NO. U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEM SK OFFICE Form PTO 1449 196880US2SRD 09/652,010 (Modified) RADE ABBEICANT LIST OF REFERENCES CITED BY APPLICANT Katsuyuki NAITO, et al. **GROUP** FILING DATE 265₺ August 31, 2000 **U.S. PATENT DOCUMENTS** FILING DATE SUB DOCUMENT **EXAMINER** DATE NAME **CLASS** IF APPROPRIATE CLASS NUMBER INITIAL 5,675,532 10/07/97 N. GEMMA, et al. B√ AA AB AC AD ΑE AF AG Technology Center 2600 ΑН ΑI ΑJ ΔK AL AM AN **FOREIGN PATENT DOCUMENTS** TRANSLATION DOCUMENT DATE COUNTRY YES NO NUMBER 05/14/90 JAPAN (with English Abstract) Х 2-125264 AO х AP 2-127649 05/16/90 JAPAN (with English Abstract) Х 10/08/90 JAPAN (with English Abstract) AO 2-250473 Х 02/16/96 JAPAN (with English Abstract) AR 8-045122 х 7-254153 10/03//95 JAPAN (with English Abstract) AS AT ΑU ΑV OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.) C. LIU, et al., Science, Vol. 261, pps. 897-899, "HIGH-DENSITY NANOSECOND CHARGE TRAPPING IN THIN FILMS OF THE PHOTOCONDUCTOR ZnODEP," August 13, 1993 AW E. BETZIG, et al., Appl. Phys. Lett., Vol. 61, No. 2, pps. 142-144, "NEAR-FIELD MAGNETO-OPTICS AND HIGH DENSITY DATA STORAGE," July 13, 1992 S. HOSAKA, et al., Thin Sold Films, Vol. 273, pps. 122-127, "SCANNING NEAR-FIELD OPTICAL MICROSCOPE WITH A LASER DIODE AND NANOMETER-SIZED BIT RECORDING," 1996 ß٧ AY S. HOSAKA, et al., J. Appl. Phys., Vol. 79, No. 10, pps. 8082-8086, "PHASE CHANGE RECORDING USING A SCANNING NEAR-FIELD OPTICAL MICROSCOPE," May 15, 1996 13 103 M **Date Considered** Examiner *Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.